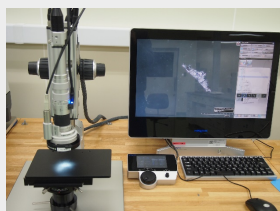




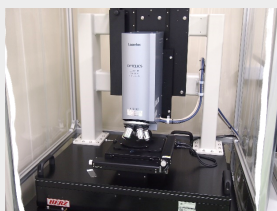
Instrumentation List for AEA - Kyoto, Japan

Foreign matter analysis • nondestructive analytical equipment (non-GMP)

Visual observation



Digital microscope



Confocal microscope

Internal observation



3D X-Ray microscopic
CT scanner (μ -CT X ray)

Elemental analysis (Inorganics like metals, minerals)



X-ray fluorescence spectrometer
(micro-XRF)



Scanning electron microscope/energy dispersive
X-ray micro-analyzer (SEM-EDX)

Ingredient analysis (Organics like resins, fibers)

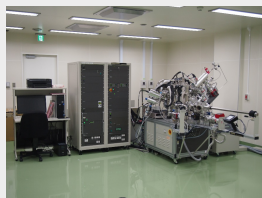


FT-IR microscope



Laser Raman microscope

Elementary analysis, Chemical bonding state analysis



X-ray photoelectron
spectroscopy (XPS)

Mass Spectrometry



Time-of-flight secondary
ion mass spectrometry (TOF-SIMS)

X-ray diffraction analysis



X-ray diffractometer

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